



PCN# : P585AAB
Issue Date : Apr. 26, 2016

DESIGN/PROCESS CHANGE NOTIFICATION

This is to inform you that a change is being made to the products listed below.

Unless otherwise indicated in the details of this notification, the identified change will have no impact on product quality, reliability, electrical, visual or mechanical performance and affected products will remain fully compliant to all published specifications. Products incorporating this change may be shipped interchangeably with existing unchanged products.

This change is planned to take effect in 90 calendar days from the date of this notification. Please work with your local Fairchild Sales Representative to manage your inventory of unchanged product if your evaluation of this change will require more than 90 calendar days.

Please contact your local Customer Quality Engineer within 30 days of receipt of this notification if you require any additional data or samples.

Implementation of change:

Expected First Shipment Date for Changed Product :Jul. 25, 2016

Expected First Date Code of Changed Product :1631

Description of Change (From) :

-Devices with pre-molded clip + Saw Singulation of Dual Asymmetric and fabricated at Fairchild Salt Lake City, UT 6-inch wafer manufacturing.

Description of Change (To) :

-Devices with metal clip + wire bonding on gate + Punch Singulation of Duall Asymmetric fabricated at Vanguard 8" foundry wafer manufacturing.

Reason for Change:

1. Process Simplification
2. To improve product quality and robustness



Affected Product(s):

FDMS3600S	FDMS3602S	FDMS3615S
FDMS3616S	FDMS3624S	



Qualification Plan	Device	Package	Process	No. of Lots
Q20150422	FDMS3602S	POWER 56	PT7 N-ch	3

Test Description:	Condition:	Standard :	Duration:	Results:
Precon	MSL1, 260C	JESD22-A113	N/A	0/1155
Autoclave	100%RH, 121C	JESD22-A102	96hrs	0/231
Highly Accelerated Stress Test	130C, 85%RH, 20V	JESD22-A110	96 hrs	0/231
High Temperature Gate Bias	150C, 20V	JESD22-A108	1000hrs	0/231
High Temperature Reverse Bias	150C, 20V	JESD22-A108	1000hrs	0/231
High Temperature Storage Life	150C	JESD22-A103	1000hrs	0/231
Power Cycle	Delta 100C, 2min on/ 2min off	JESD22-A122	10000 cycles	0/231
Temperature Cycle	-55C , 150C	JESD22-A104	1000cycles	0/231



Title : Qualification Report for PCN : P585AAB

Date : Apr. 25, 2016

Affected devices :

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Product	Customer Part Number	BBB	Drawing
FDMS3600S		Y	N
FDMS3615S		Y	N
FDMS3624S		Y	N

Qualification Test Summary :

Qualification Plan	Device	Package	Process	No. of Lots
Q20150422	FDMS3602S	POWER 56	PT7 N-ch	3

Test Description:	Condition:	Standard :	Duration:	Results:
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High Temperature Storage Life	150C	JESD22-A103	1000hrs	0/231
Power Cycle	Delta 100C, 2min on/ 2min off	JESD22-A122	10000 cycles	0/231
Temperature Cycle	-55C, 150C	JESD22-A104	1000cycles	0/231

The selection methodology of qualification vehicles is aligned with JESD47 and if automotive devices are impacted by the PCN the selection of qualification vehicles is also align with the requirements in AEC-Q100 or AEC-Q101

Please contact your local Customer Quality Engineer if you have any questions concerning this data.